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International IOR Rectifier

PD - 94547A **IRLR7833** IRLU7833
HEXFET® Power MOSFET

V _{DSS}	R _{DS(on)} max	Qg
30V	4.5m $Ω$	33nC

D-Pak IRLR7833 IRLU7833

Applications

- High Frequency Synchronous Buck Converters for Computer Processor Power
- High Frequency Isolated DC-DC Converters with Synchronous Rectification for Telecom and Industrial Use

Benefits

- Very Low RDS(on) at 4.5V V_{GS}
- Ultra-Low Gate Impedance
- Fully Characterized Avalanche Voltage and Current

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	30	V
V_{GS}	Gate-to-Source Voltage	± 20	7
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	140④	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	99⊕	А
I _{DM}	Pulsed Drain Current ①	560	
P _D @T _C = 25°C	Maximum Power Dissipation ©	140	W
P _D @T _C = 100°C	Maximum Power Dissipation ^⑤	71	7
	Linear Derating Factor	0.95	W/°C
T_J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf in (1.1N m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.05	
$R_{\theta JA}$	Junction-to-Ambient (PCB Mount) ^⑤		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	•

Notes ① through ⑤ are on page 11

Static @ T_J = 25°C (unless otherwise specified)

<u> </u>					
Parameter	Min.	Typ.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250 \mu A$
Breakdown Voltage Temp. Coefficient		19		mV/°C	Reference to 25°C, I _D = 1mA
Static Drain-to-Source On-Resistance		3.6	4.5	mΩ	V _{GS} = 10V, I _D = 15A ⊕
		4.4	5.5	1	V _{GS} = 4.5V, I _D = 12A ④
Gate Threshold Voltage	1.4		2.3	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
Gate Threshold Voltage Coefficient		-6.0	_	mV/°C	
Drain-to-Source Leakage Current			1.0	μΑ	$V_{DS} = 24V, V_{GS} = 0V$
			150	1	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-100	Ī	V _{GS} = -20V
Forward Transconductance	66			S	$V_{DS} = 15V, I_D = 12A$
Total Gate Charge		33	50		
Pre-Vth Gate-to-Source Charge		8.7	_	1	$V_{DS} = 16V$
Post-Vth Gate-to-Source Charge		2.1		nC	$V_{GS} = 4.5V$
Gate-to-Drain Charge		13			$I_D = 12A$
Gate Charge Overdrive		9.9	_	İ	See Fig. 16
Switch Charge (Q _{gs2} + Q _{gd})		15			
Output Charge		22		nC	$V_{DS} = 16V, V_{GS} = 0V$
Turn-On Delay Time		14			V _{DD} = 15V, V _{GS} = 4.5V ④
Rise Time		6.9		1	$I_D = 12A$
Turn-Off Delay Time		23		ns	Clamped Inductive Load
Fall Time		15		1	
Input Capacitance		4010	_		$V_{GS} = 0V$
Output Capacitance		950		pF	$V_{DS} = 15V$
Reverse Transfer Capacitance		470		1	f = 1.0MHz
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Gate Threshold Voltage Coefficient Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Forward Transconductance Total Gate Charge Pre-Vth Gate-to-Source Charge Post-Vth Gate-to-Source Charge Gate Charge Overdrive Switch Charge (Q _{gs2} + Q _{gd}) Output Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Gate Threshold Voltage Coefficient Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Forward Transconductance Fortal Gate Charge Pre-Vth Gate-to-Source Charge Post-Vth Gate-to-Source Charge Gate-to-Drain Charge Gate Charge Overdrive Switch Charge (Q _{gs2} + Q _{gd}) Output Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Output Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage 30 Breakdown Voltage Temp. Coefficient — Static Drain-to-Source On-Resistance — Gate Threshold Voltage 1.4 Gate Threshold Voltage Coefficient — Drain-to-Source Leakage Current — Gate-to-Source Forward Leakage — Gate-to-Source Reverse Leakage — Forward Transconductance 66 Total Gate Charge — Pre-Vth Gate-to-Source Charge — Gate-to-Drain Charge — Gate Charge Overdrive — Switch Charge (Q _{gs2} + Q _{gd}) — Output Charge — Turn-On Delay Time — Rise Time — Turn-Off Delay Time — Fall Time — Input Capacitance — Output Capacitance —	Drain-to-Source Breakdown Voltage 30 — — Breakdown Voltage Temp. Coefficient — 19 — Static Drain-to-Source On-Resistance — 3.6 4.5 — 4.4 5.5 Gate Threshold Voltage Coefficient — -6.0 — Drain-to-Source Leakage Current — 1.0 — Drain-to-Source Leakage Current — 1.0 — Gate-to-Source Forward Leakage — — 100 Gate-to-Source Forward Leakage — — 100 Gate-to-Source Reverse Leakage — — 100 Forward Transconductance 66 — — Total Gate Charge — 8.7 — Pre-Vth Gate-to-Source Charge — 8.7 — Post-Vth Gate-to-Source Charge — 2.1 — Gate Charge Overdrive — 9.9 — Switch Charge (Q _{gs2} + Q _{gd}) — 15 — Output Charge — 22	Drain-to-Source Breakdown Voltage 30 — V Breakdown Voltage Temp. Coefficient — 19 — mV/°C Static Drain-to-Source On-Resistance — 3.6 4.5 mΩ — 4.4 5.5 — 4.4 5.5 Gate Threshold Voltage 1.4 — 2.3 V Gate Threshold Voltage Coefficient — -6.0 — mV/°C Drain-to-Source Leakage Current — -6.0 — mV/°C Drain-to-Source Leakage Current — 1.0 μA — — 150 nA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 100 nA Forward Transconductance 66 — — S Total Gate Charge — 3.7 — nC Gate-to-Drain Charge — 2.1 — nC Gate Charge Overdrive — 9.9 <

Avalanche Characteristics

	Parameter	Тур.	Max.	Units
E _{AS}	Single Pulse Avalanche Energy 2		530	mJ
I _{AR}	Avalanche Current ①		20	Α
E _{AR}	Repetitive Avalanche Energy ①		14	mJ

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			140®		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			560		integral reverse
	(Body Diode) ①⑥					p-n junction diode.
V_{SD}	Diode Forward Voltage		—	1.0	V	$T_J = 25$ °C, $I_S = 12A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		39	58	ns	$T_J = 25$ °C, $I_F = 12A$, $V_{DD} = 15V$
Q _{rr}	Reverse Recovery Charge		37	55	nC	di/dt = 100A/μs ④
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

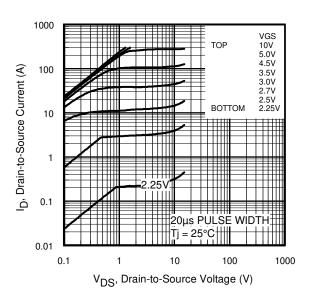


Fig 1. Typical Output Characteristics

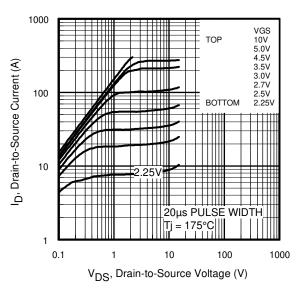


Fig 2. Typical Output Characteristics

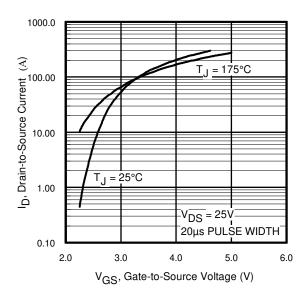


Fig 3. Typical Transfer Characteristics

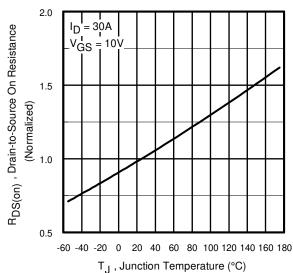


Fig 4. Normalized On-Resistance vs. Temperature

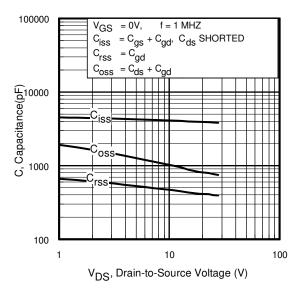


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

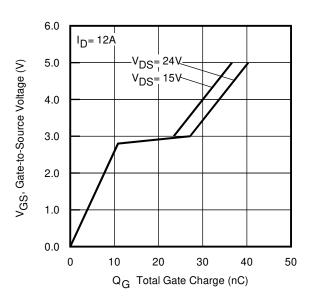


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

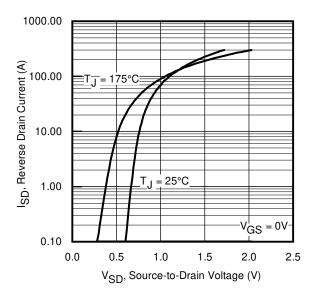


Fig 7. Typical Source-Drain Diode Forward Voltage

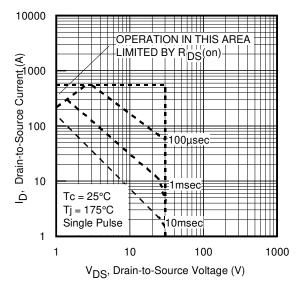
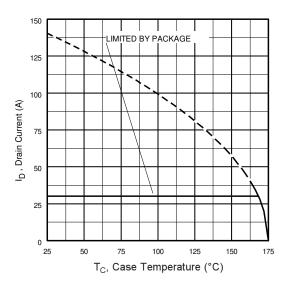


Fig 8. Maximum Safe Operating Area



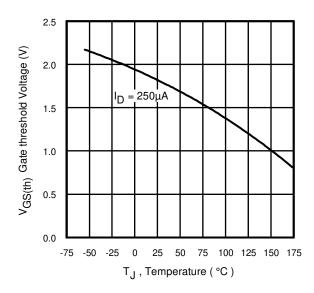


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Threshold Voltage vs. Temperature

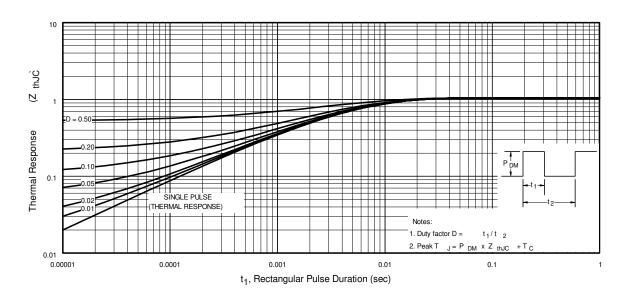


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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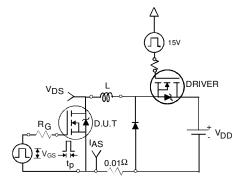


Fig 12a. Unclamped Inductive Test Circuit

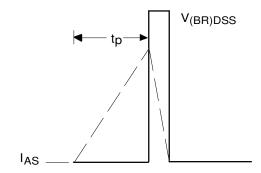


Fig 12b. Unclamped Inductive Waveforms

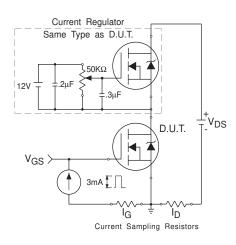


Fig 13. Gate Charge Test Circuit

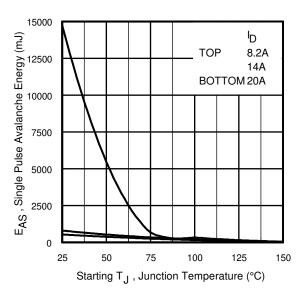


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

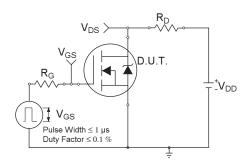


Fig 14a. Switching Time Test Circuit

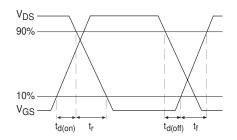


Fig 14b. Switching Time Waveforms

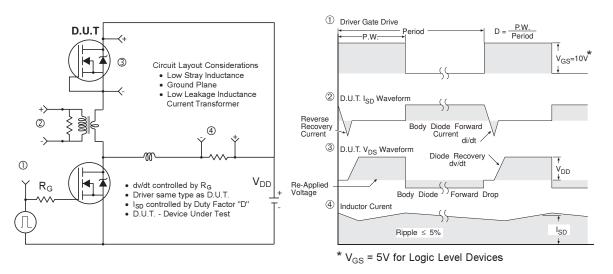


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

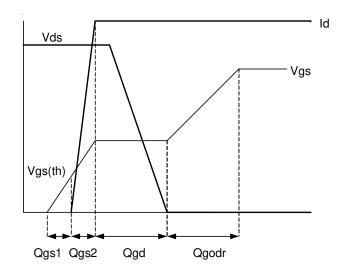


Fig 16. Gate Charge Waveform

Power MOSFET Selection for Non-Isolated DC/DC Converters

Control FET

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the $R_{\text{ds(on)}}$ of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by;

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms ${\rm Q_{gs2}}$ and ${\rm Q_{oss}}$ which are new to Power MOSFET data sheets.

 Q_{gs2} is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements, Q_{gs1} and Q_{gs2} , can be seen from Fig 16.

 Q_{gs2} indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to I_{dmax} at which time the drain voltage begins to change. Minimizing Q_{gs2} is a critical factor in reducing switching losses in Q1.

 $\rm Q_{oss}$ is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how $\rm Q_{oss}$ is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's $\rm C_{ds}$ and $\rm C_{dg}$ when multiplied by the power supply input buss voltage.

Synchronous FET

The power loss equation for Q2 is approximated by;

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

*dissipated primarily in Q1.

For the synchronous MOSFET Q2, $R_{ds(on)}$ is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge Q_{oss} and reverse recovery charge Q_{rr} both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and $V_{\rm in}.$ As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of $Q_{\rm gd}/Q_{\rm gs1}$ must be minimized to reduce the potential for Cdv/dt turn on.

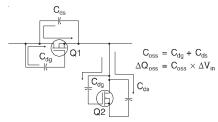
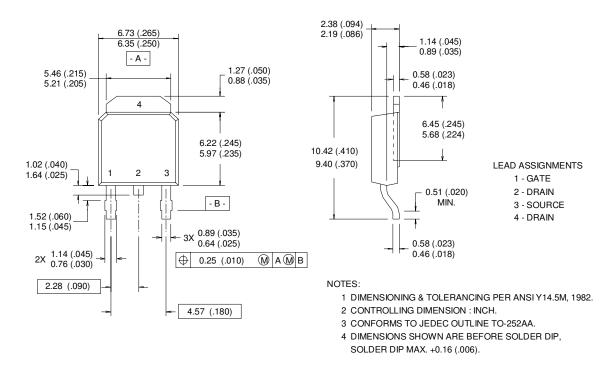


Figure A: Qoss Characteristic

TO-252AA (D-Pak) Package Outline

Dimensions are shown in millimeters (inches)

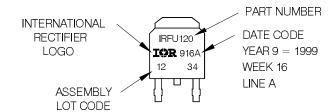


TO-252AA (D-Pak) Part Marking Information

EXAMPLE: THIS IS AN IRFR120 WITH ASSEMBLY

LOT CODE 1234 ASSEMBLED ON WW 16, 1999

IN THE ASSEMBLY LINE "A"

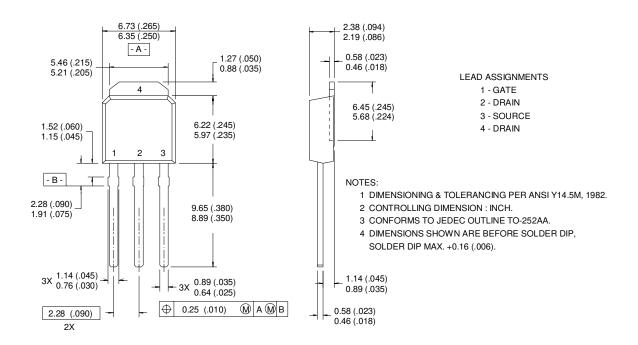


International

TOR Rectifier

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



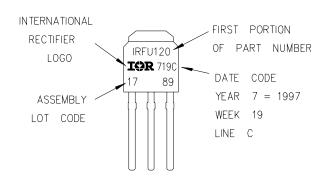
I-Pak (TO-251AA) Part Marking Information

EXAMPLE: THIS IS AN IRFU120

LOT CODE 1789

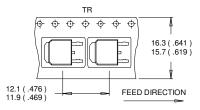
ASSEMBLED ON WW 19, 1997

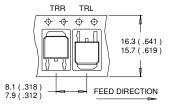
IN THE ASSEMBLY LINE "C"



D-Pak (TO-252AA) Tape & Reel Information

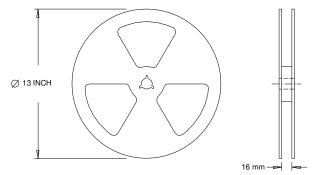
Dimensions are shown in millimeters (inches)





NOTES :

- 1. CONTROLLING DIMENSION : MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES

1. OUTLINE CONFORMS TO EIA-481.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- Starting $T_J = 25$ °C, L = 2.6mH, $R_G = 25\Omega$, $I_{AS} = 20A$.
- ③ Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 30A.
- ⑤ When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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Visit us at www.irf.com for sales contact information.03/04

Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/